# Dual N-Channel Power MOSFET with Integrated Schottky

30 V, High Side 18 A / Low Side 23 A, Dual N-Channel SO8FL

#### **Features**

- Co-Packaged Power Stage Solution to Minimize Board Space
- Low Side MOSFET with Integrated Schottky
- Minimized Parasitic Inductances
- Optimized Devices to Reduce Power Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### **Applications**

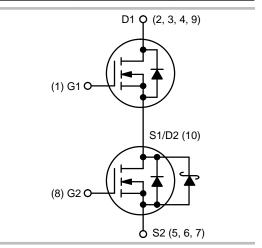
- DC-DC Converters
- System Voltage Rails
- Point of Load



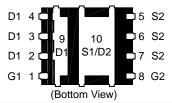
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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
Q1 Top FET	6.5 mΩ @ 10 V	40 A
30 V	10 mΩ @ 4.5 V	18 A
Q2 Bottom	4.1 mΩ @ 10 V	22.4
FET 30 V	6.2 mΩ @ 4.5 V	23 A



#### **PIN CONNECTIONS**



#### MARKING DIAGRAM



DFN8 CASE 506BX



4902NF = Specific Device Code

A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.

#### **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise stated)

Parameter		Symbol	Value	Unit		
Drain-to-Source Voltage	Q1	V <sub>DSS</sub>	30	V		
Drain-to-Source Voltage	Q2					
Gate-to-Source Voltage	Q1	$V_{GS}$	±20	V		
Gate-to-Source Voltage			Q2			
Continuous Drain Current R <sub>0JA</sub> (Note 1)	ontinuous Drain Current $R_{\theta JA}$ (Note 1) $T_A = 25^{\circ}C$					
		T <sub>A</sub> = 85°C	1		9.7	1
		T <sub>A</sub> = 25°C	Q2		17.5	A
		T <sub>A</sub> = 85°C			12.6	1
Power Dissipation		T <sub>A</sub> = 25°C	Q1	P <sub>D</sub>	1.90	W
RθJA (Note 1)			Q2		1.99	1
Continuous Drain Current $R_{\theta JA} \le 10 \text{ s}$ (Note 1)		T <sub>A</sub> = 25°C	Q1	I <sub>D</sub>	18.2	
		T <sub>A</sub> = 85°C			13.1	A
	Steady	T <sub>A</sub> = 25°C	Q2		23	
	State	T <sub>A</sub> = 85°C			16.6	
Power Dissipation		T <sub>A</sub> = 25°C	Q1	$P_{D}$	3.45	W
$R_{\theta JA} \le 10 \text{ s (Note 1)}$			Q2		3.45	
Continuous Drain Current		$T_A = 25^{\circ}C$	Q1	I <sub>D</sub>	10.3	
R <sub>θJA</sub> (Note 2)		$T_A = 85^{\circ}C$			7.4	A
		$T_A = 25^{\circ}C$	Q2		13.3	
		$T_A = 85^{\circ}C$			9.6	
Power Dissipation		T <sub>A</sub> = 25 °C	Q1	$P_{D}$	1.10	W
R <sub>θJA</sub> (Note 2)			Q2		1.16	
Pulsed Drain Current		TA = 25°C tp = 10 μs	Q1	I <sub>DM</sub>	60	Α
		ιρ = 10 μs	Q2		80	
Operating Junction and Storage Temperature	Q1	$T_J$ , $T_{STG}$	-55 to +150	°C		
	Q2					
Source Current (Body Diode)	Q1	I <sub>S</sub>	3.4	Α		
	Q2		4.9			
Drain to Source dV/dt		dV/dt	6.0	V/ns		
Single Pulse Drain-to-Source Avalanche Energy (T. $V_{DD} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_L = XX A_{pk}, L = 0.1 \text{ mH}, R_{C}$	Q1	EAS	28.8	mJ		
ν <sub>DD</sub> – 30 ν, ν <sub>GS</sub> – 10 ν, ι <sub>L</sub> = ΛΛ Α <sub>pk</sub> , L = 0.1 ΠΠ, Κ <sub>C</sub>	Q2	EAS	36.5			
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)				TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Surface—mounted on FR4 board using 1 sq—in pad, 2 oz Cu.

2. Surface—mounted on FR4 board using the minimum recommended pad size of 100 mm².

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	FET	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 3)	Q1	$R_{\theta JA}$	65.9	
	Q2	]	62.8	1
Junction-to-Ambient - Steady State (Note 4)	Q1	$R_{\theta JA}$	113.2	°C/W
	Q2	]	108	C/VV
Junction-to-Ambient - (t ≤ 10 s) (Note 3)	Q1	$R_{\theta JA}$	36.2	
	Q2		36.2	

- Surface–mounted on FR4 board using 1 sq-in pad, 2 oz Cu.
   Surface–mounted on FR4 board using the minimum recommended pad size of 100 mm².

Parameter	FET	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS								
Drain-to-Source Break-	Q1	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
down Voltage	Q2		$V_{GS} = 0 V$ ,	I <sub>D</sub> = 1.0 mA	30			
Drain-to-Source Break-	Q1	V <sub>(BR)DSS</sub>				18		mV /
down Voltage Temperature Coefficient	Q2	T <sub>J</sub>				15		•C
Zero Gate Voltage Drain	Q1	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25°C			1	μΑ
Current			V <sub>DS</sub> = 24 V	T <sub>J</sub> = 125°C			10	
	Q2		$V_{GS} = 0 \text{ V},$ $V_{DS} = 24 \text{ V}$	T <sub>J</sub> = 25°C			500	
Gate-to-Source Leakage	Q1	I <sub>GSS</sub>	$V_{GS} = 0 V,$	VDS = ±20 V			±100	nA
Current	Q2						±100	1
ON CHARACTERISTICS (Not	e 5)							
Gate Threshold Voltage	Q1	V <sub>GS(TH)</sub>	$V_{GS} = VDS$ , $I_D = 250 \mu A$		1.2		2.2	V
	Q2				1.2		2.2	]
Negative Threshold Temperature Coefficient	Q1	V <sub>GS(TH)</sub> /				4.5		mV / °C
ature Coefficient	Q2	ТЈ				4.0		
Drain-to-Source On Resistance	Q1	R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}$	I <sub>D</sub> = 10 A		5.2	6.5	
ance			$V_{GS} = 4.5 \text{ V}$	I <sub>D</sub> = 10 A		8.0	10	mΩ
	Q2		$V_{GS} = 10 \text{ V}$	I <sub>D</sub> = 15 A		3.3	4.1	
			$V_{GS} = 4.5 \text{ V}$	I <sub>D</sub> = 15 A		5.0	6.2	
Forward Transconductance	Q1	9FS	$V_{DS} = 1.5$	V, I <sub>D</sub> = 10 A		28		S
	Q2					35		
CHARGES, CAPACITANCES	& GATE	RESISTANCI	Ξ					
Input Capacitance		Cupa				1150		
input Capacitance	Q2	Q2 C <sub>ISS</sub>				1590		
Output Capacitance	Q1	C <sub>OSS</sub> V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 15		MHz Vpo = 15 V		360		pF
Output Oapaoltarioo	Q2	OSS	$v_{GS} = 0$ $v, i = i$ will $iz, v_{DS} = i3$ $v$			813		] "
Reverse Capacitance	Q1	Cooo				105		
11010130 Oapaoltanoe	Q2 C <sub>RSS</sub>					83		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- 5. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
  6. Switching characteristics are independent of operating junction temperatures.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	FET	Symbol	Test Co	ndition	Min	Тур	Max	Unit
CHARGES, CAPACITANCES	& GATE	RESISTANC	E		•			
T : 10 : 0:	Q1				9.7			
Total Gate Charge	Q2	$Q_{G(TOT)}$				11.5		1
<b>T</b>	Q1					1.1		
Threshold Gate Charge	Q2	Q <sub>G(TH)</sub>		.=		1.4		nC
00	Q1		$V_{GS} = 4.5 \text{ V}, V_{DS}$	= 15 V; I <sub>D</sub> = 10 A		3.3		
Gate-to-Source Charge	Q2	$Q_{GS}$				4.2		
	Q1	_				3.7		
Gate-to-Drain Charge	Q2	$Q_{GD}$				3.4		
	Q1	_				19.1		
Total Gate Charge	Q2	$Q_{G(TOT)}$	$V_{GS} = 10 \text{ V}, V_{DS}$	= 15 V; I <sub>D</sub> = 10 A		24.9		nC
SWITCHING CHARACTERIS	STICS (No	te 6)						
	Q1					9.0		
Turn-On Delay Time	Q2	t <sub>d(ON)</sub>			10.5		ns	
Rise Time	Q1	- t <sub>r</sub>				15		
	Q2		Vcs = 4.5 V.	Voc = 45 V Voc = 15 V		15.2		
	Q1	t <sub>d(OFF)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 10 \text{ A}, R_{G} = 3.0 \Omega$			14		
Turn-Off Delay Time	Q2					17.7		
	Q1					4.0		
Fall Time	Q2	t <sub>f</sub>				4.7		1
SWITCHING CHARACTERIS	STICS (No	te 6)			•			
	Q1					6.0		
Turn-On Delay Time	Q2	t <sub>d(ON)</sub>				7.0		
	Q1					14		
Rise Time	Q2	t <sub>r</sub>	V <sub>CS</sub> = 10 V.	Vne = 15 V.		14		7
	Q1		$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 10 \text{ A}, R_{G} = 3.0 \Omega$			17		ns
Turn-Off Delay Time	Q2	t <sub>d(OFF)</sub>				22		
	Q1					3.0		
Fall Time	Q2	t <sub>f</sub>				3.3		
DRAIN-SOURCE DIODE CH	IARACTE	RISTICS						
			V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.75	1.0	
	Q1		$I_S = 3 A$	$T_J = 125$ °C $T_J = 25$ °C	1	0.62		
Forward Voltage		$V_{SD}$	V <sub>GS</sub> = 0 V,		1	0.37	0.70	- V
	Q2		$I_S = 2 A$	T <sub>J</sub> = 125°C	1	0.31	<del>                                     </del>	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ . 6. Switching characteristics are independent of operating junction temperatures.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	FET	Symbol Test Condition		Min	Тур	Max	Unit
DRAIN-SOURCE DIODE CH	ARACTE	RISTICS					
D	Q1				23		
Reverse Recovery Time	Q2	t <sub>RR</sub>			24.5		1
Ohanna Tina	Q1				12		ns nC
Charge Time	Q2	ta	V 0V 1 /1 400 A/ 5 1 0 A		13		
D'ank anna Tara	Q1	d	$V_{GS} = 0 \text{ V}, d_{IS}/d_t = 100 \text{ A/}\mu\text{s}, I_S = 3 \text{ A}$		11		
Discharge Time	Q2	tb	-		11.5		
Daviere Daviere Chare	Q1	0			12		
Reverse Recovery Charge	Q2	$Q_{RR}$			24		
PACKAGE PARASITIC VALU	IES						
Course Industria	Q1	,			0.38		nH
Source Inductance	Q2	L <sub>S</sub>			0.65		
Desir la desta es	Q1		T 0700		0.054		nH
Drain Inductance	Q2	L <sub>D</sub>			0.007		
Gate Inductance Q1		T <sub>A</sub> = 25°C		1.5		T	
	Q2	L <sub>G</sub>			1.5		nH
Onto Booletone	Q1	1			0.8		
Gate Resistance	Gate Resistance Q2 R <sub>G</sub>			0.8		Ω	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFD4902NFT1G	DFN8 (Pb-Free)	1500 / Tape & Reel
NTMFD4902NFT3G	DFN8 (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

<sup>6.</sup> Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS - Q1**

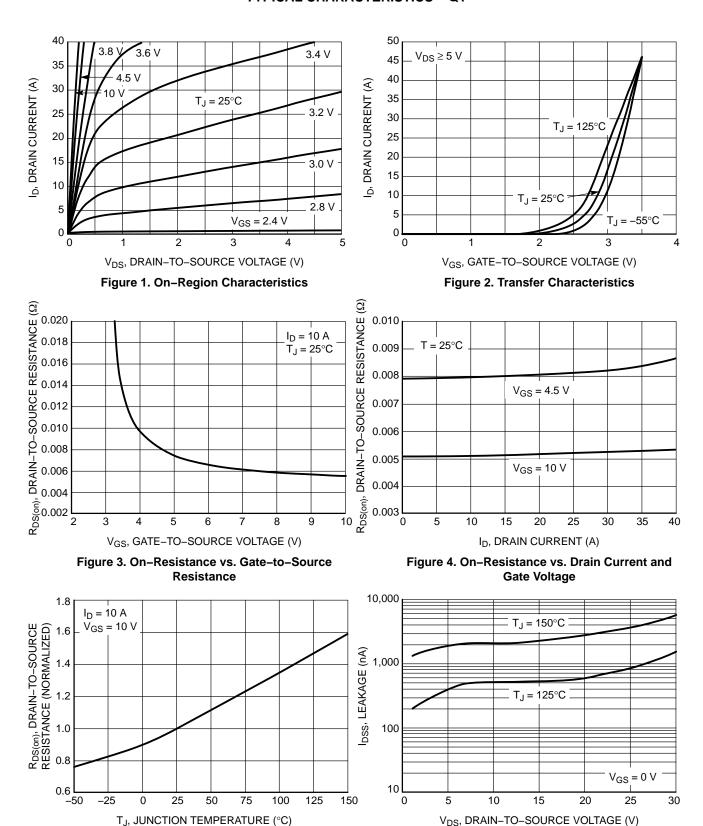


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS - Q1**

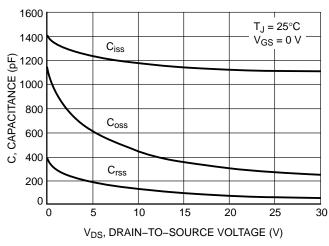


Figure 7. Capacitance Variation

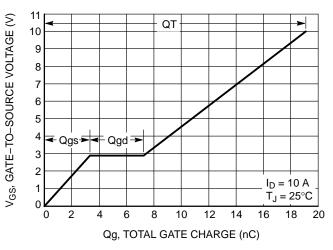


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

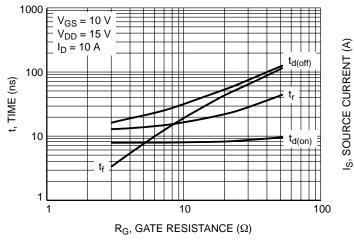


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

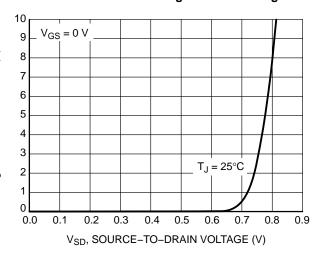
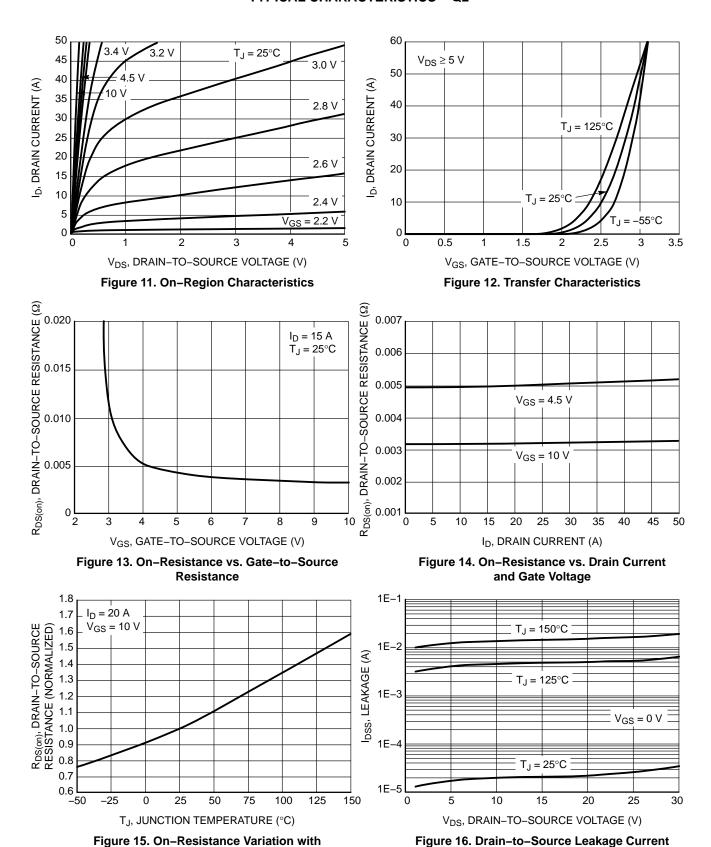


Figure 10. Diode Forward Voltage vs. Current

#### **TYPICAL CHARACTERISTICS - Q2**



vs. Voltage

**Temperature** 

#### **TYPICAL CHARACTERISTICS - Q2**

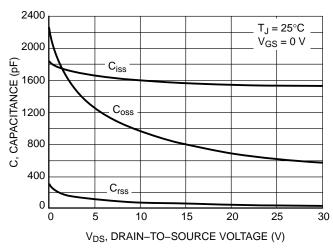


Figure 17. Capacitance Variation

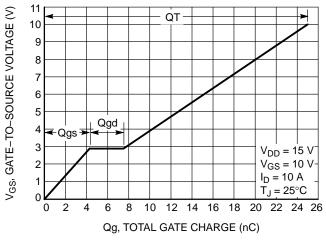


Figure 18. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

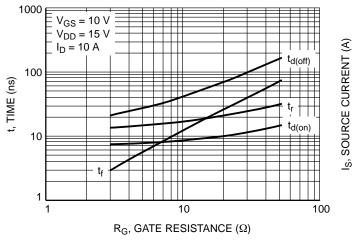


Figure 19. Resistive Switching Time Variation vs. Gate Resistance

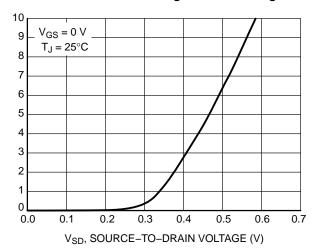
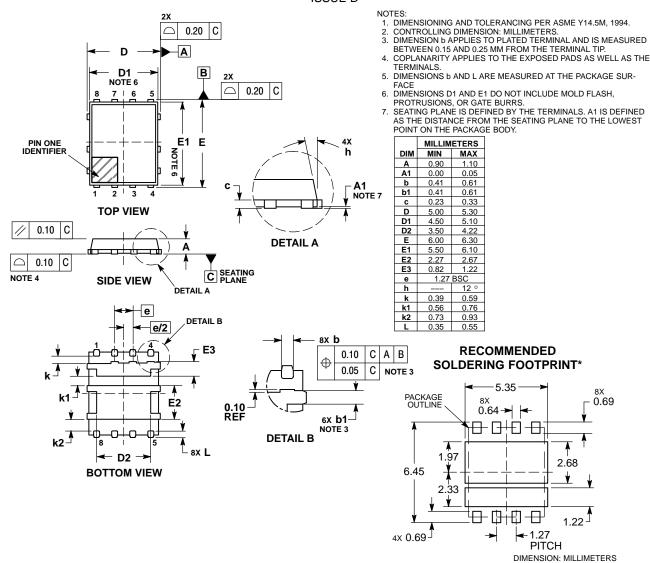


Figure 20. Diode Forward Voltage vs. Current

#### PACKAGE DIMENSIONS

#### DFN8 5x6, 1.27P Dual Flag (SO8FL-Dual-Asymmetrical)

CASE 506BX ISSUE D



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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